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Application/Control No.	Applicant(s)/Patent under Reexamination	-
10/510,481	HAYASHI ET AL.	
Examiner	Art Unit	
James F. Hook	3754	

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Class	Subclass	Date	Examiner
138	137, 141	6/20/2007	JH
428	36.91	6/20/2007	JH
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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East BRS (US only) see search	6/20/2007	.JH
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